



LinBIST for ADCs

Automated Built-In Self-Test

LinBIST automatically creates Built-In Self-Test (BIST) blocks for ADCs, **simplifying test access and reducing test time and cost.**

FEATURES

- Pushbutton BIST for ADCs
- SFDR, THD, DNL, INL, Offset, Gain, Noise etc. measurements
- No external components
- Complete on-chip processing
- Minimal on-chip test circuitry (primarily digital)
- I2C test interface options
- Seamless integration with existing design flow
- Synthesized and verified at design time
- Intuitive GUI driven control
- Decimates production test costs
- Eliminates need for production Analog ATE and CTO cards
- Accelerates test development
- Process options include 65nm, 90nm and 0.18um

PERFORMANCE

- >96db THD capability
- >100dB SFDR capability
- Up to 24-bit ADCs supported

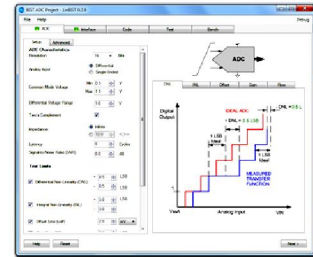
DESCRIPTION

LinBIST's powerful GUI allows you to create efficient digital BIST designs for ADCs without having to write a single line of HDL (Verilog or VHDL).

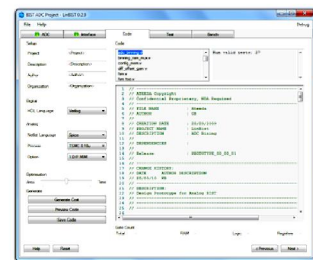
APPLICATIONS

ADC BIST for Analog Mixed-Signal ICs - Audio, Video and more.
Wafer probe, final, field and continuous monitoring test (Automotive, consumer, safety critical etc.)

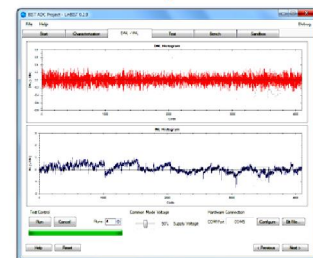
LinBIST User Interface



Enter test requirements...



...then output customized IP Block



Characterise devices on the bench

